

VFE Calibration – Pedestals and Bad Channels in the VFE Electronics



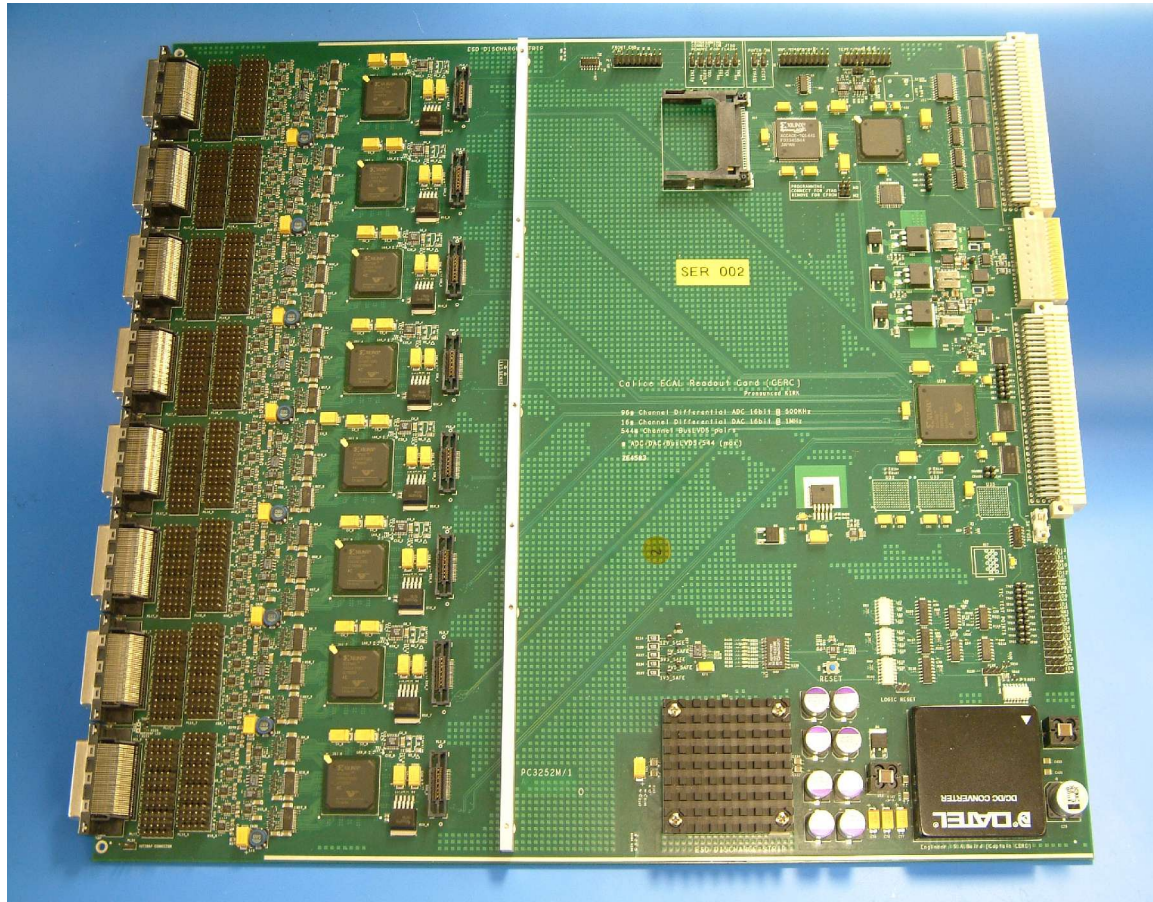
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CALICE Test-Beam Meeting, Monday, 6th March 2006

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- Determining the Bad Channels
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- Future plans

Organisation of the Readout Electronics



- One ECAL crate with 21 slots (0-20)
- Three of these slots (7, 15 & 19) contain Calice Readout Cards (CRCs).
- Each CRC contains 8 FE FPGAs. Not all appear to be connected to slabs.
- Each FE deals with 12 VFE chips (0-11).
- Each VFE chip deals with 18 channels (0-17).
- Therefore, each FE deals with 216 channels.

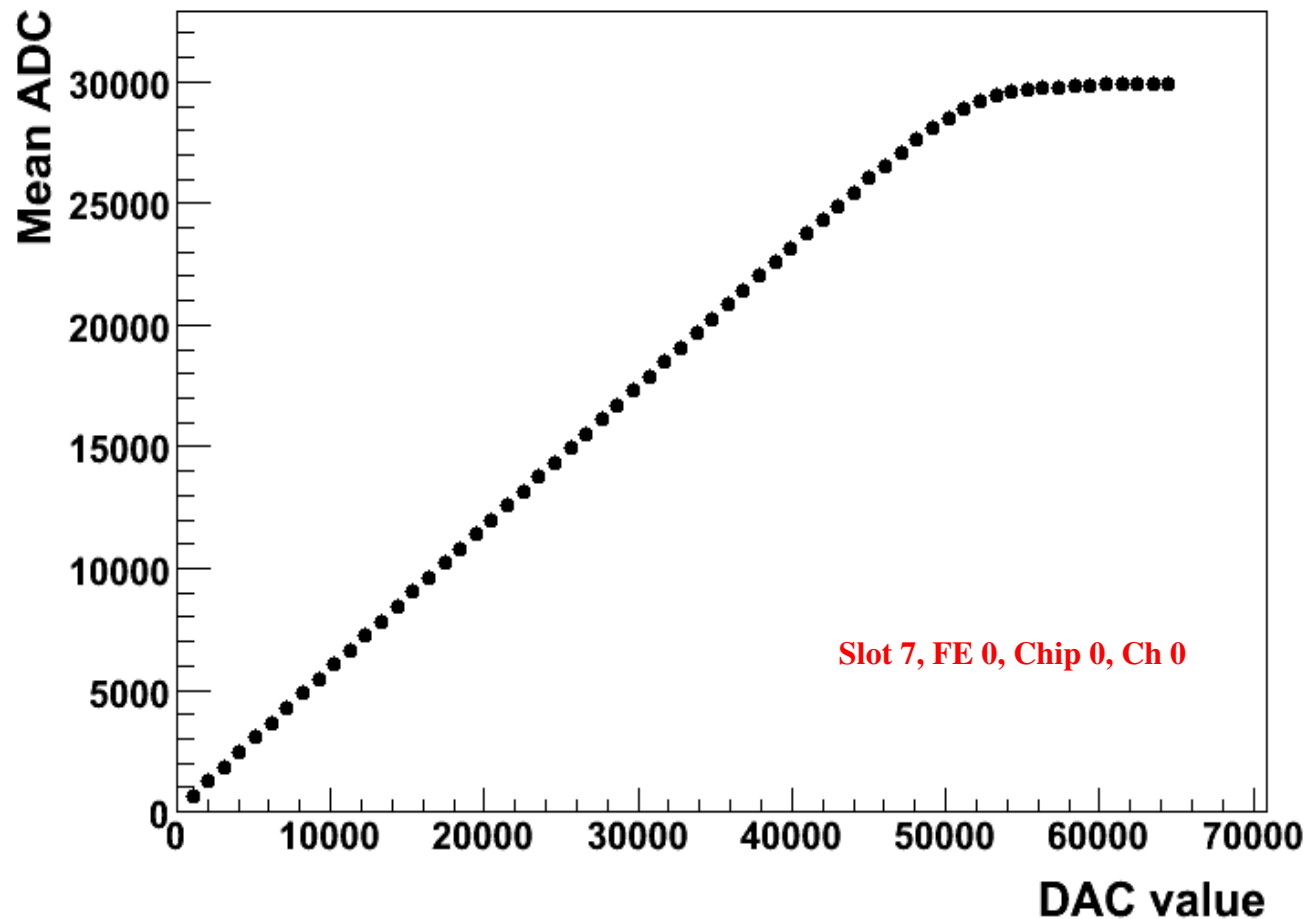
Determination of Bad Channels and Pedestals

- The goal here is to develop an (automated) calibration procedure.
- Shift crew could periodically run a special preconfigured *calibration run*. An automated analysis is then performed upon the collected calibration data to allow bad channels to be found and pedestals determined (amongst other things no doubt).
- Allows good calibration of the system and the information can be incorporated in to the simulation software (via Marlin Processor for example).
- Work is underway in developing such a calibration procedure.
- Paul recently took a calibration run at DESY.
- Run 200062.
- I (with Paul's valuable help!) am developing the analysis procedure.
- This talk will discuss what's been done so far.

Calibration Run 200062

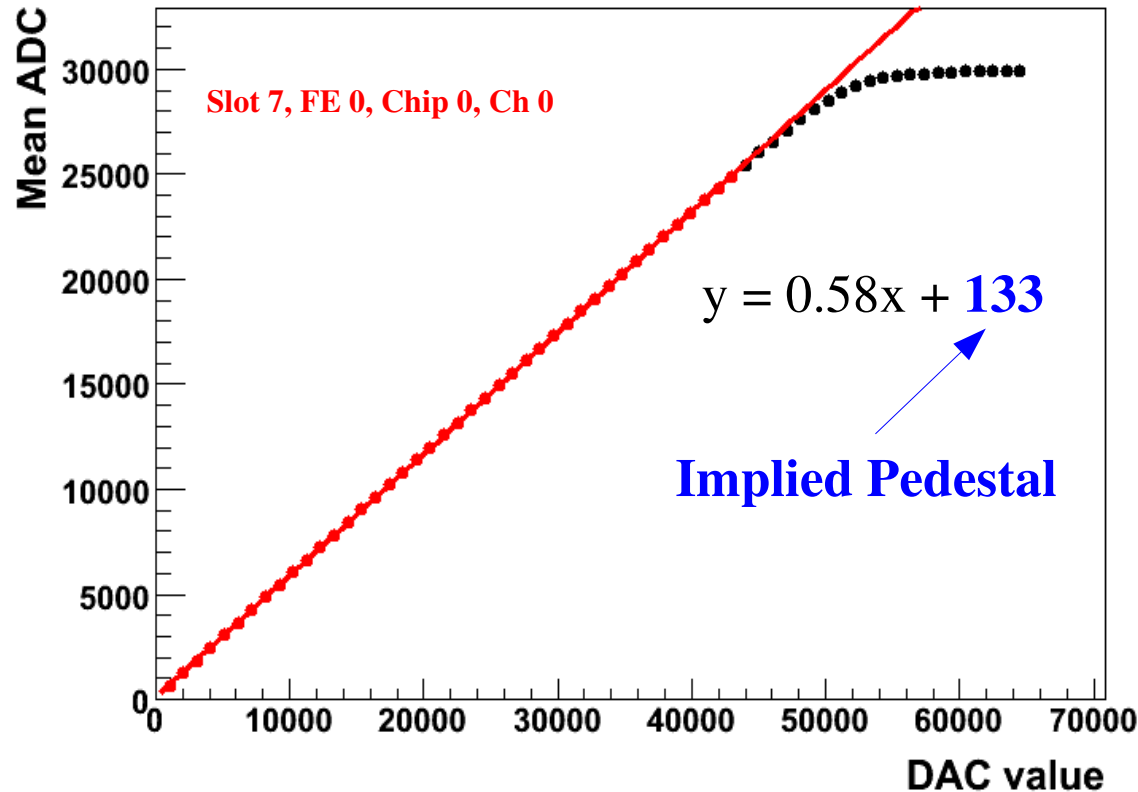
- Each VFE channel was pulsed with a calibration pulse (DAC) of varying magnitude.
- DAC size given by $i*1024$ where $i=0,1,2, \dots, 63$

Channel Diagnostics - Introduction



- A channel is diagnosed by plotting the mean ADC value for each DAC value.
- A healthy channel is characterised by a linear response of the Mean ADC with increasing DAC value.
- Saturation occurs at a DAC value of ~50000 corresponding to a mean ADC of ~30000.

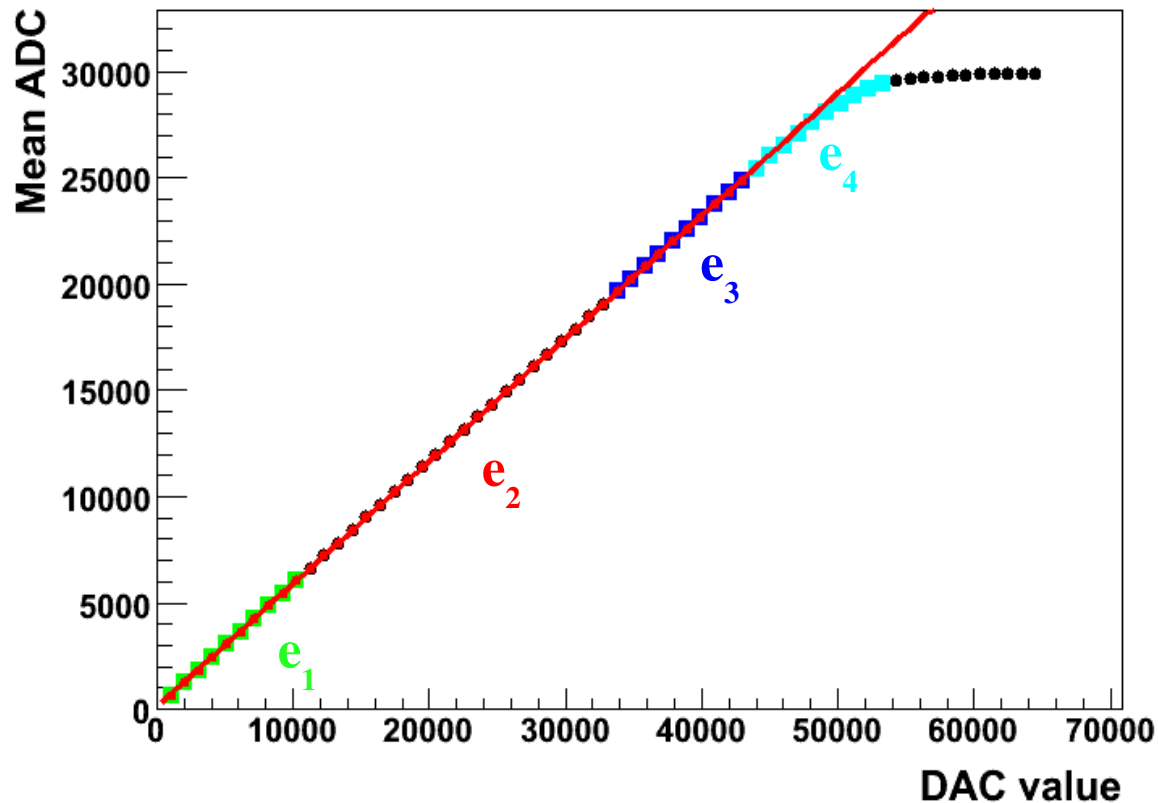
Channel Diagnostics - Fitting



- Each channel is fitted with a first order polynomial.
- Linear regression formulae are used directly rather than fitting using ROOT.
- Much faster when the whole procedure has to be repeated 1000s of times.
- Only the first 42 points are fitted (red).

- To fit $f(a, b) = ax + b$ to straight line data use:

$$b = \frac{SS_{xy}}{S_{xx}} \quad a = \bar{y} - b\bar{x} \quad \text{where} \quad SS_{xx} = \sum (x_i - \bar{x})^2 \quad SS_{yy} = \sum (y_i - \bar{y})^2 \quad SS_{xy} = \sum (x_i - \bar{x})(y_i - \bar{y})$$



- How rigorous is the fitting procedure. Need various tests. These tests not only test the quality of the fitting but also the quality of the channel itself.

- Calculate

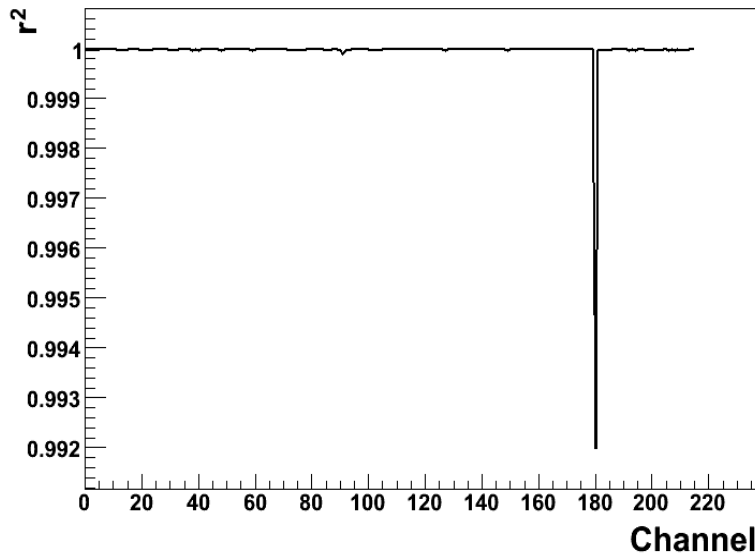
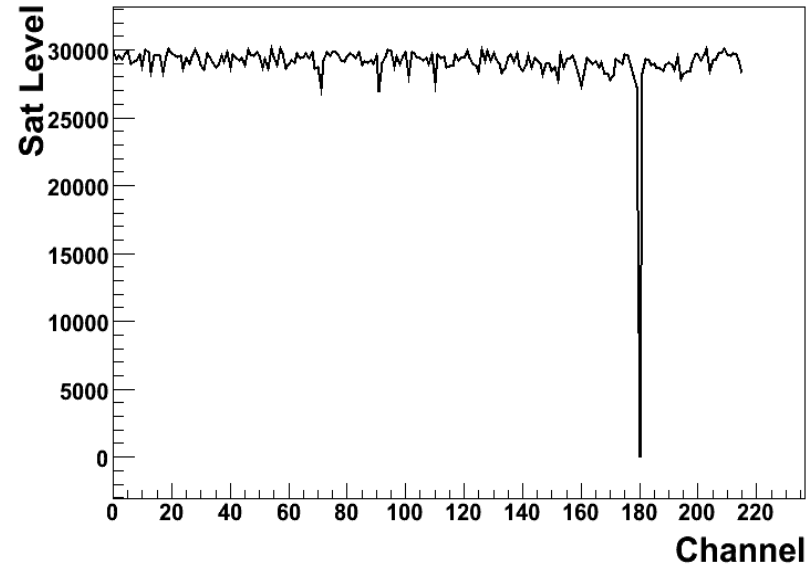
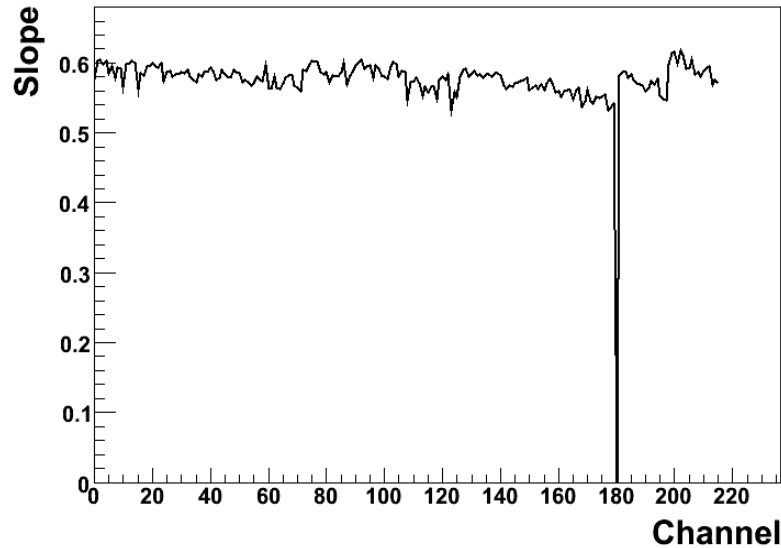
$$r^2 = \frac{SS_{xy}^2}{S_{xx} S_{yy}}$$

- Should be 1 if the fit is good.
- Next, consider the residuals in various regions.

- e_1 , residuals for the first 10 fitted points. Should be ~ 0 (test for linearity at low DAC values)
- e_2 , residuals for the all fitted points. Should be ~ 0 (test for linearity across the entire fitted range)
- e_3 , residuals for the last 10 fitted points. Should be ~ 0 (test for linearity at high DAC values)
- e_4 , residuals for the next 10 points after the last fitted point. Should be > 0 (test for saturation in the expected region)

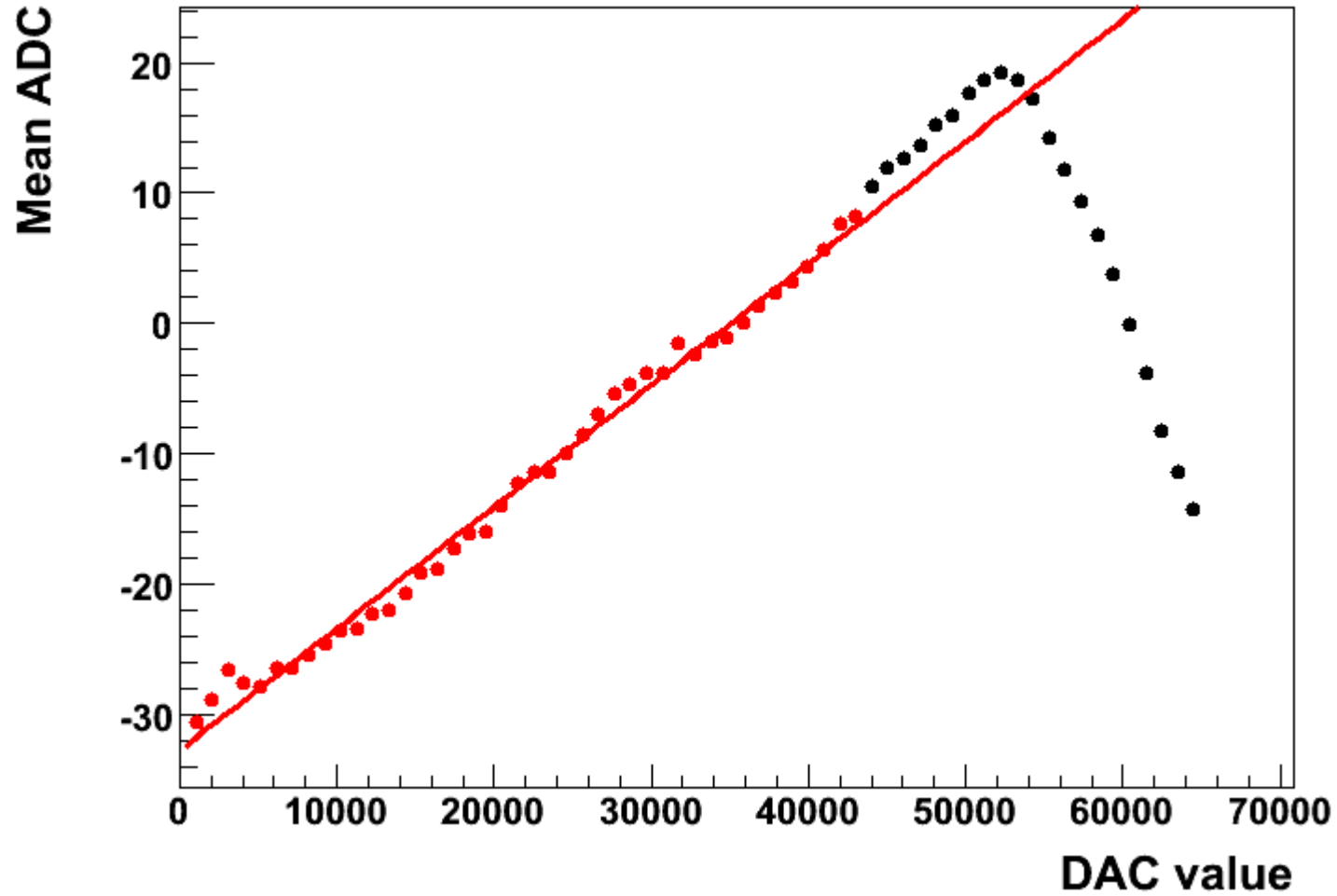
Channel Diagnostics – Study of Slot 7, FE 0

- Let's look at all channels in one FE. Say, Slot 7, FE0.

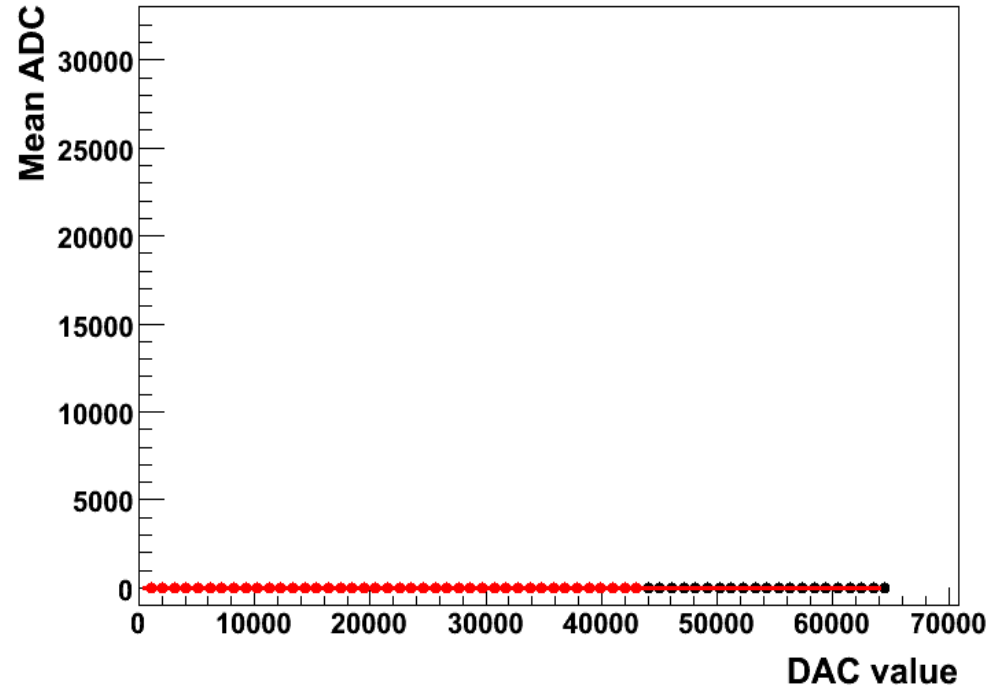
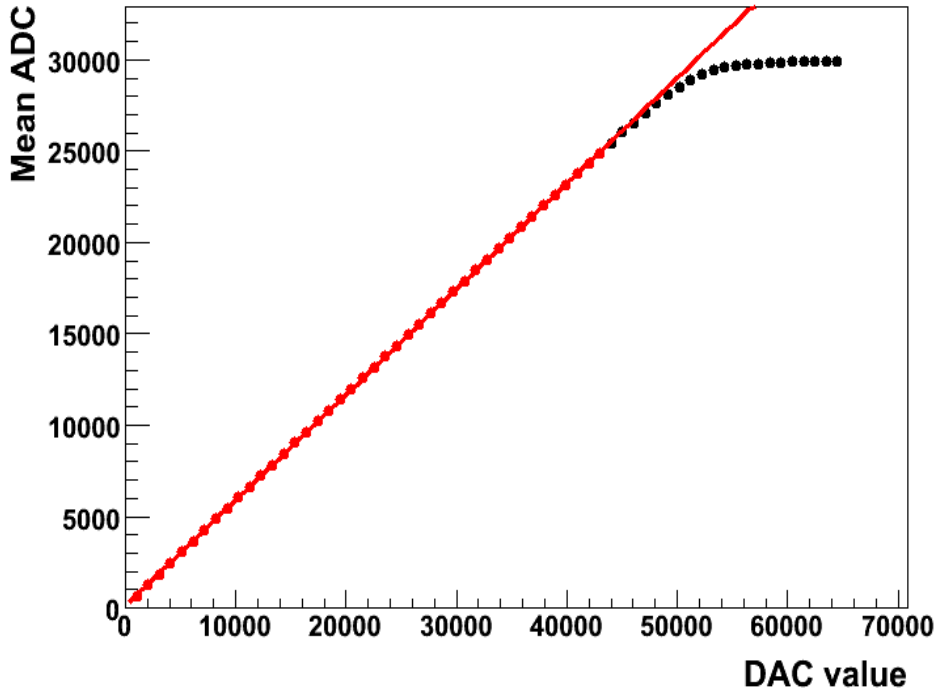


- 180 looks like a Bad Channel
- Let's take a closer look at 180

Channel Diagnostics – Study of Slot 7, FE 0, Channel 180

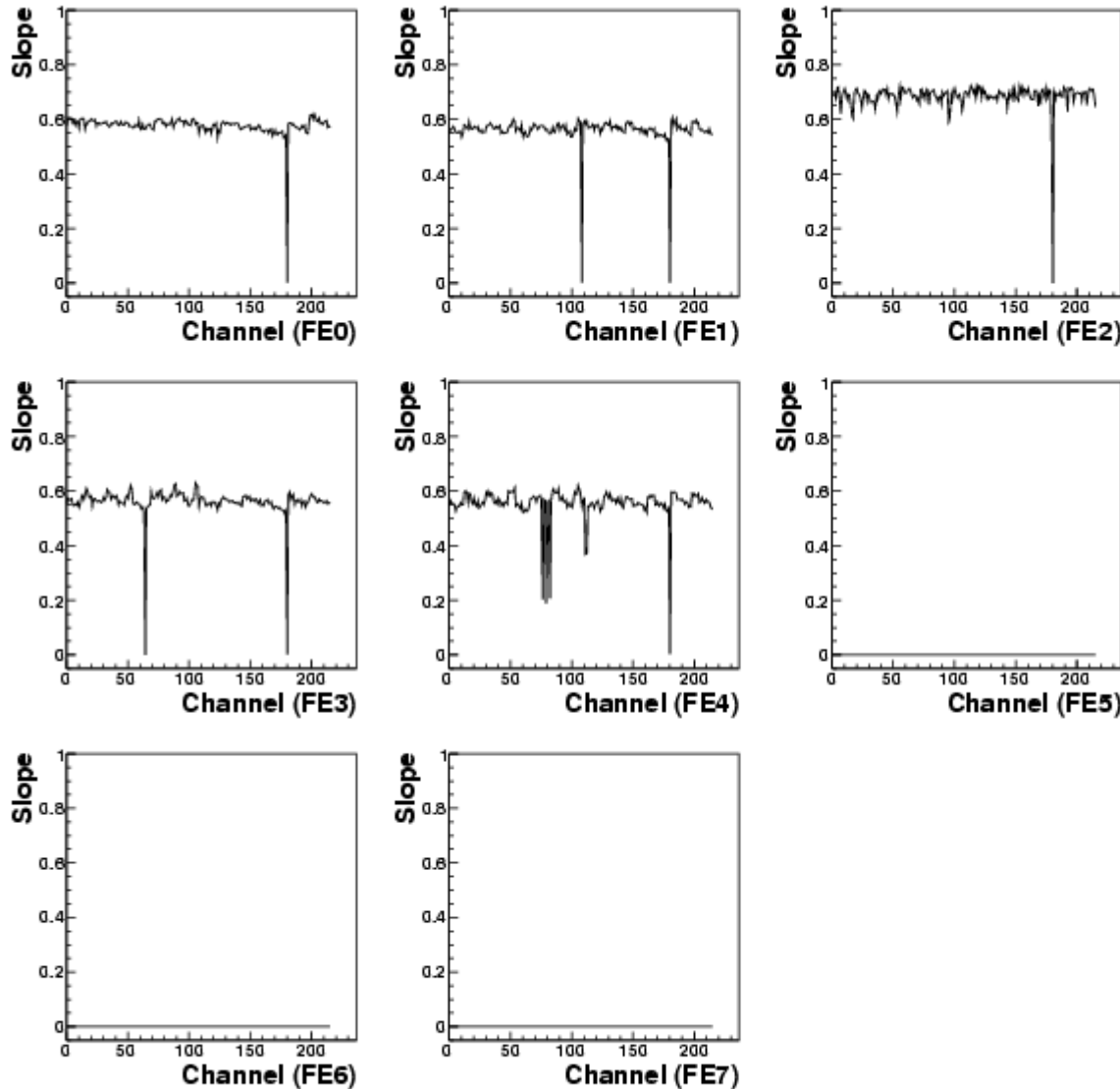


Channel Diagnostics – Study of Slot 7, FE 0, Channel 180



- Channel looks dead!
- Now let's look at the entire readout

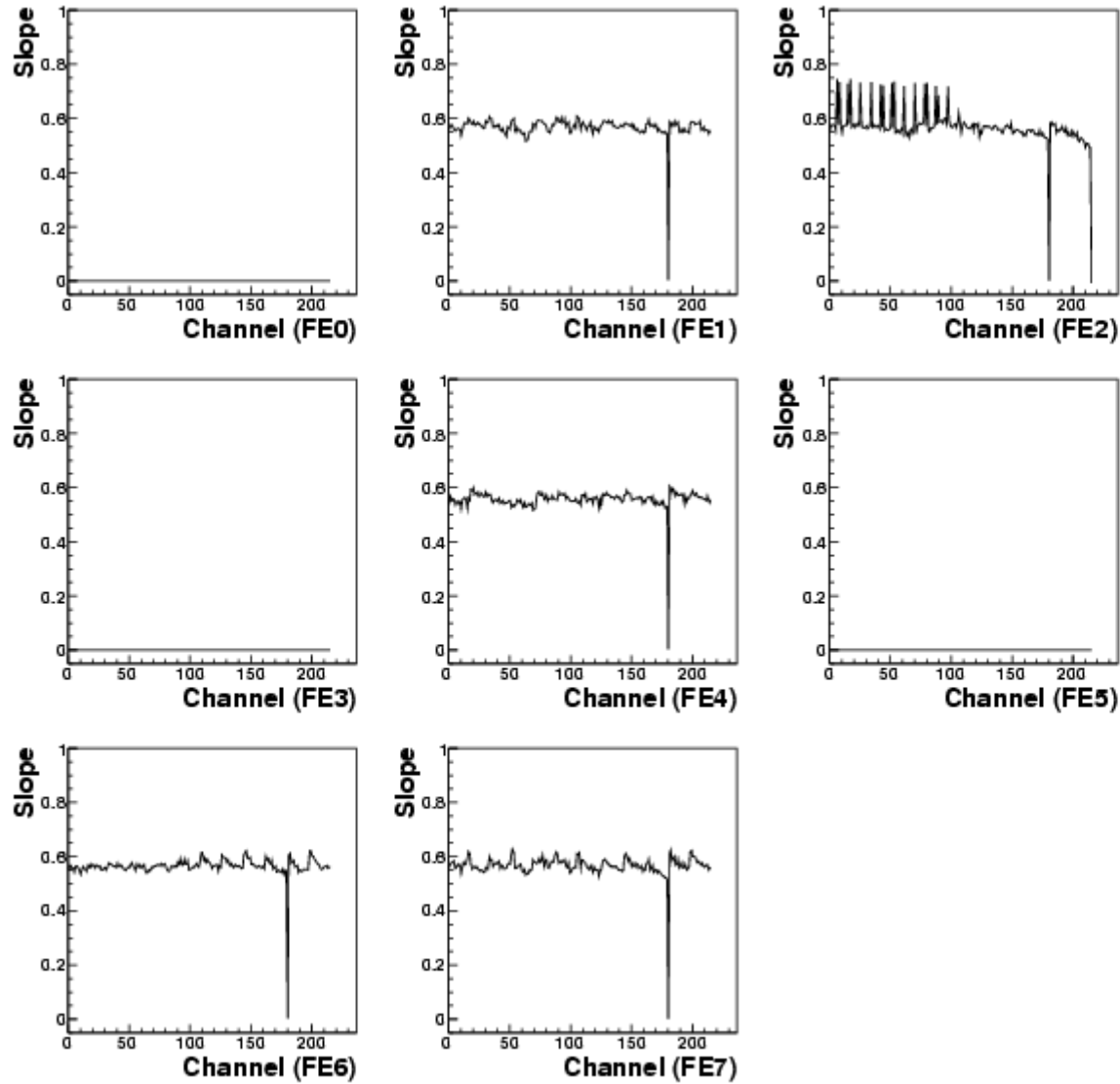
Channel Diagnostics – Study of Slot 7



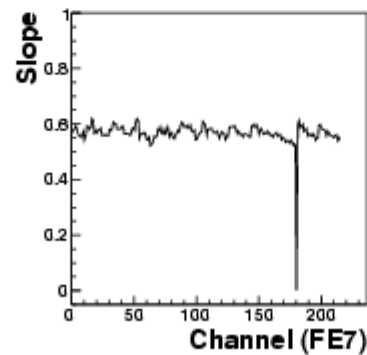
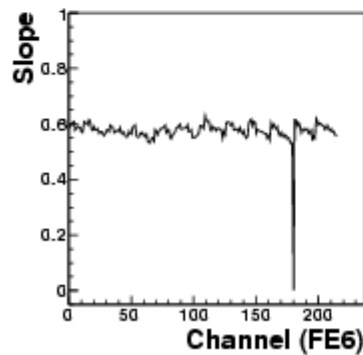
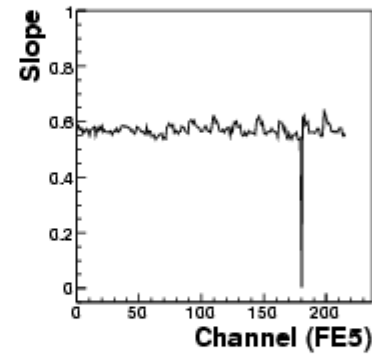
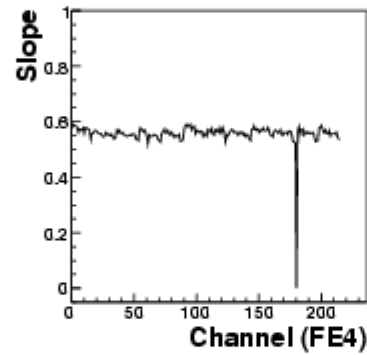
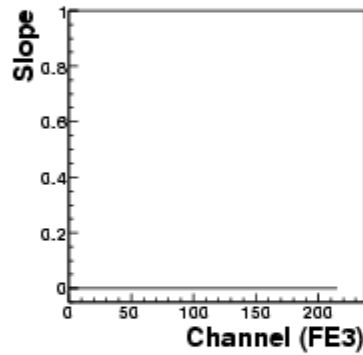
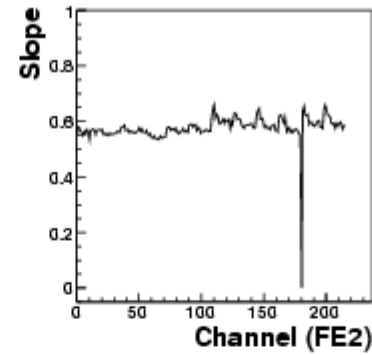
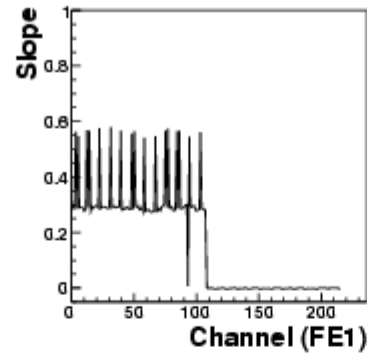
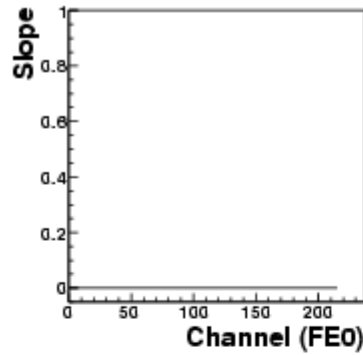
← Suspicious looking slope values. We'll come back to this.

- Not all FEs are active.
- Possible bad chip in FE4.

Channel Diagnostics – Study of Slot 15



Channel Diagnostics – Study of Slot 19



Channel Diagnostics – Summary



- Firstly, there is far too much information on this topic to show it all during this talk.
- Website has been set up at

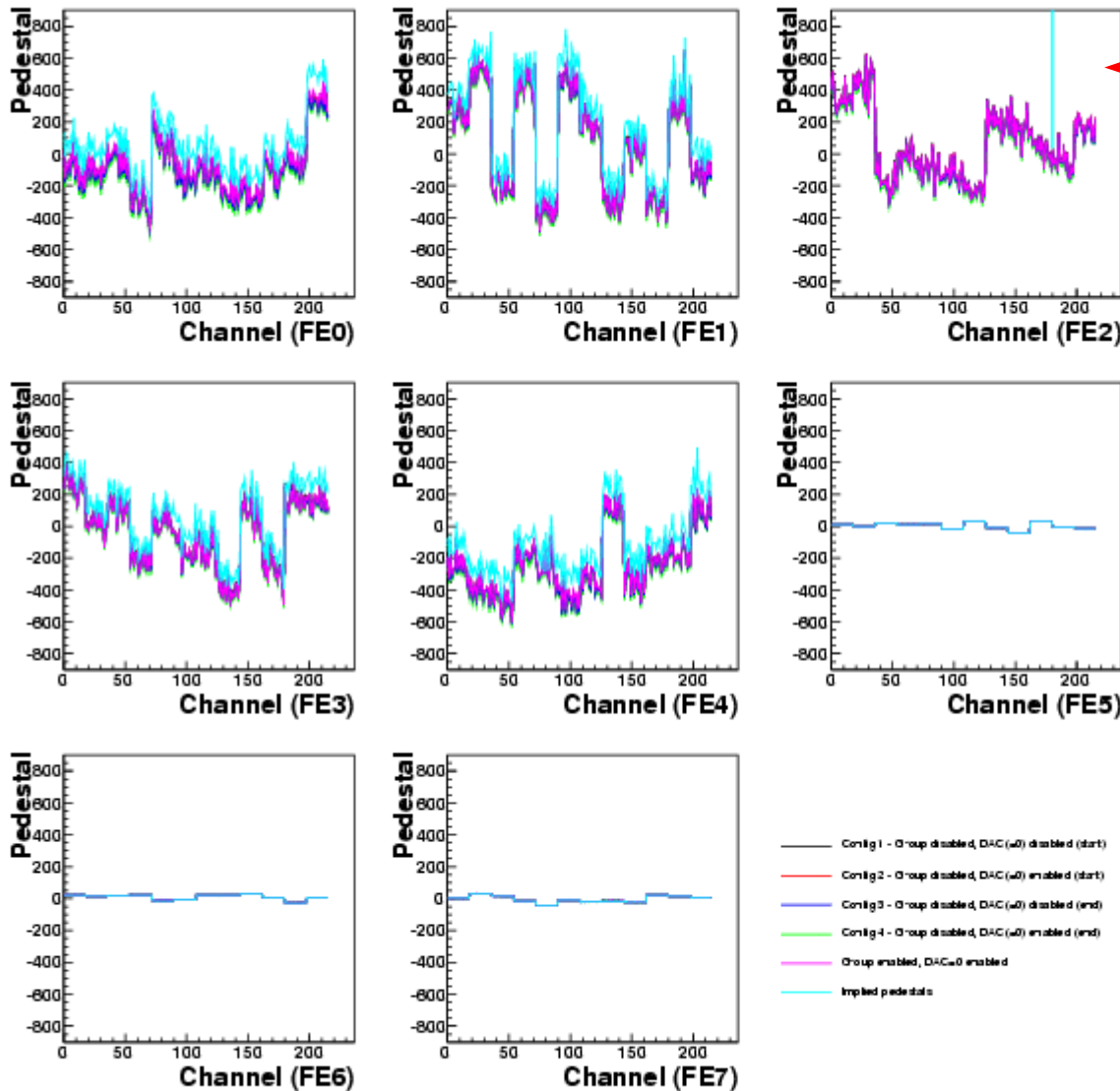
http://www.hep.ucl.ac.uk/~cta/calice/bad_channels/bad_channels.html

- This site shows all the plots that have been produced during the study presented in this talk (for all channels).
- Must decide on the criteria to be used to label a channel as bad.
- Then a list of bad channels can be added to the website. After each calibration run, the website can be automatically updated with a list of bad channels.

Pedestals

- Various methods of measuring the pedestal in each channel have been used
- The pedestals were measured:
 - At the beginning of the run
 - With the Group disabled and the DAC disabled.
 - **With the Group disabled and the DAC enabled.**
 - At the end of the run
 - **With the Group disabled and the DAC disabled.**
 - **With the Group disabled and the DAC enabled.**
- **The pedestals were also measured with the Group enabled and the DAC enabled (and set to 0).**
- **In addition the implied pedestals were measured by taking the intercept of the straight line fits, discussed in the last section.**
- These are all just slightly different ways of measuring the pedestal and they should give consistent results.

Pedestals – Slot 7

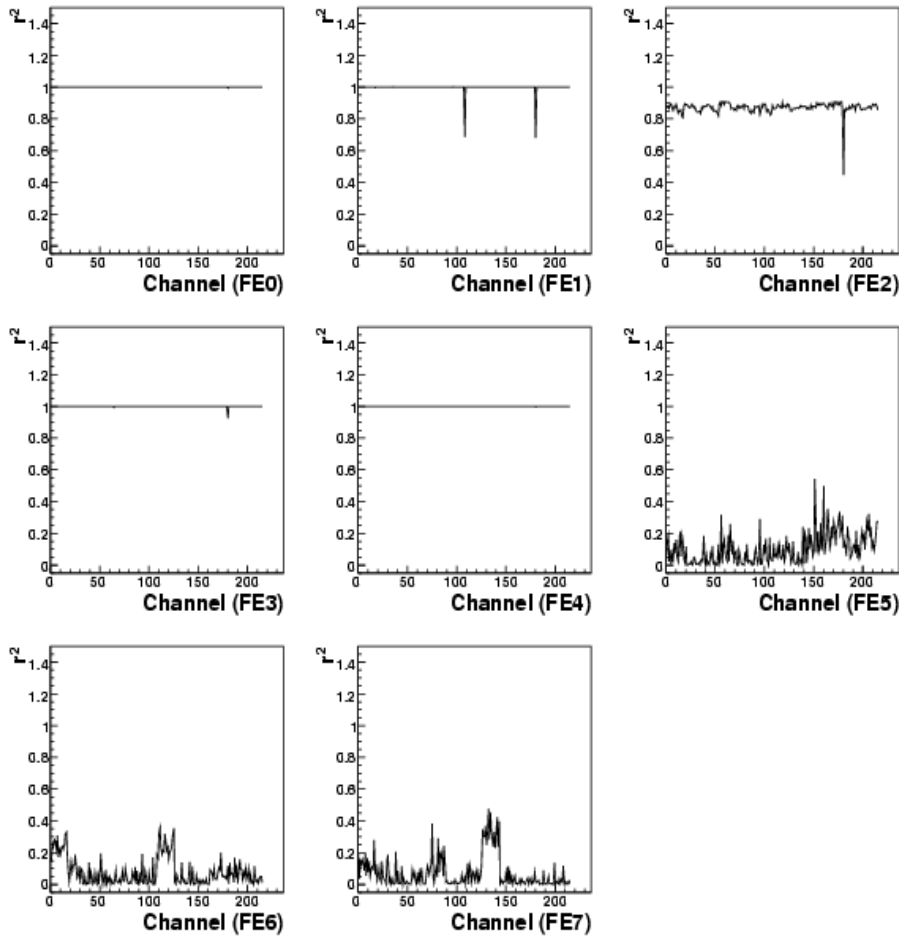


← This was the FE with the suspicious looking slope values. The implied pedestals are huge.

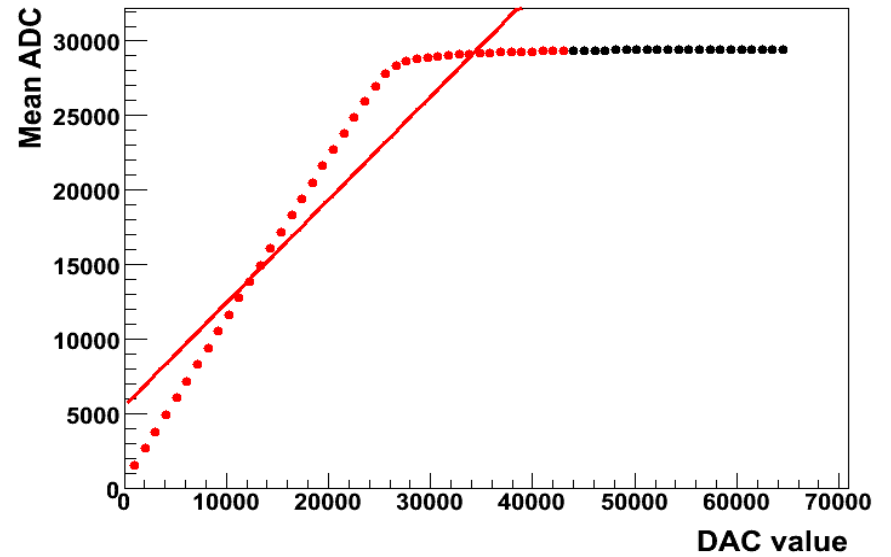
- Noticeable chip-to-chip variation.
- Implied pedestals seem to be consistently higher than the other measures.

— Config 1 - Group disabled, DAC(u0) disabled (start)
— Config 2 - Group disabled, DAC(u0) enabled (start)
— Config 3 - Group disabled, DAC(u0) disabled (end)
— Config 4 - Group disabled, DAC(u0) enabled (end)
— Group enabled, DAC=0 enabled
— Implied pedestals

Fit qualities– Slot 7

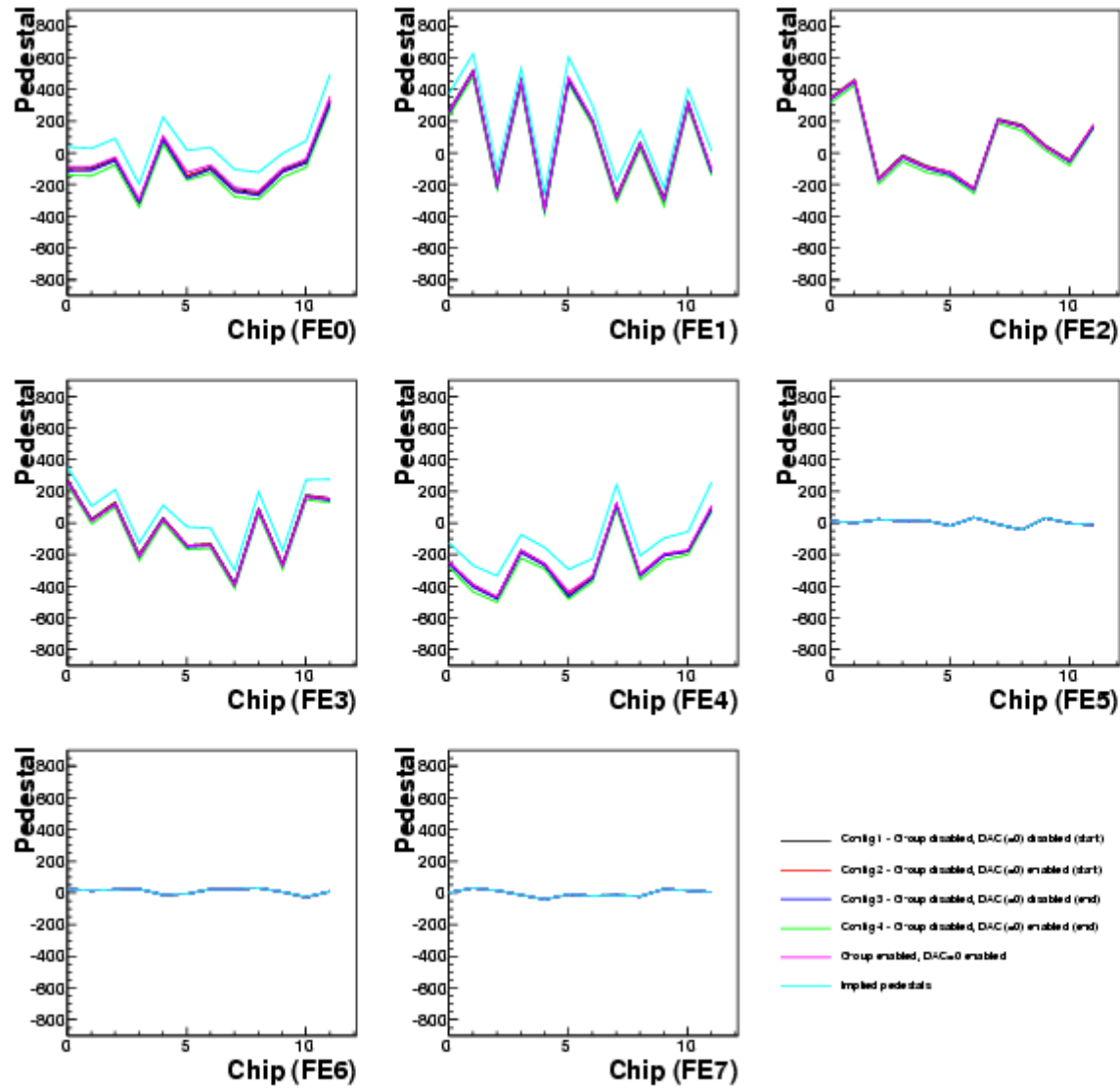


Let's look at channel 0 of FE2

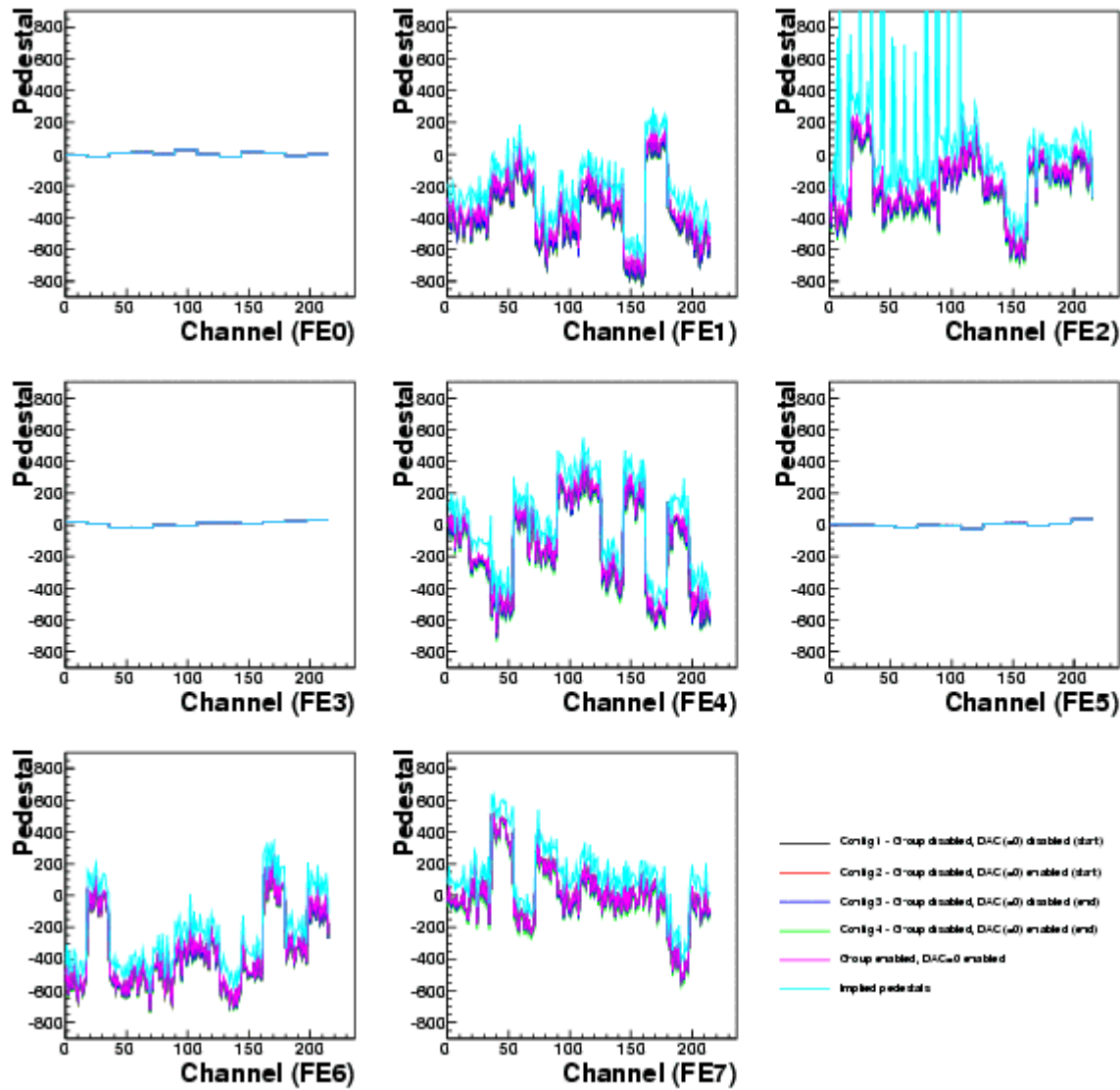


- Looks like the channels are too sensitive in FE2.

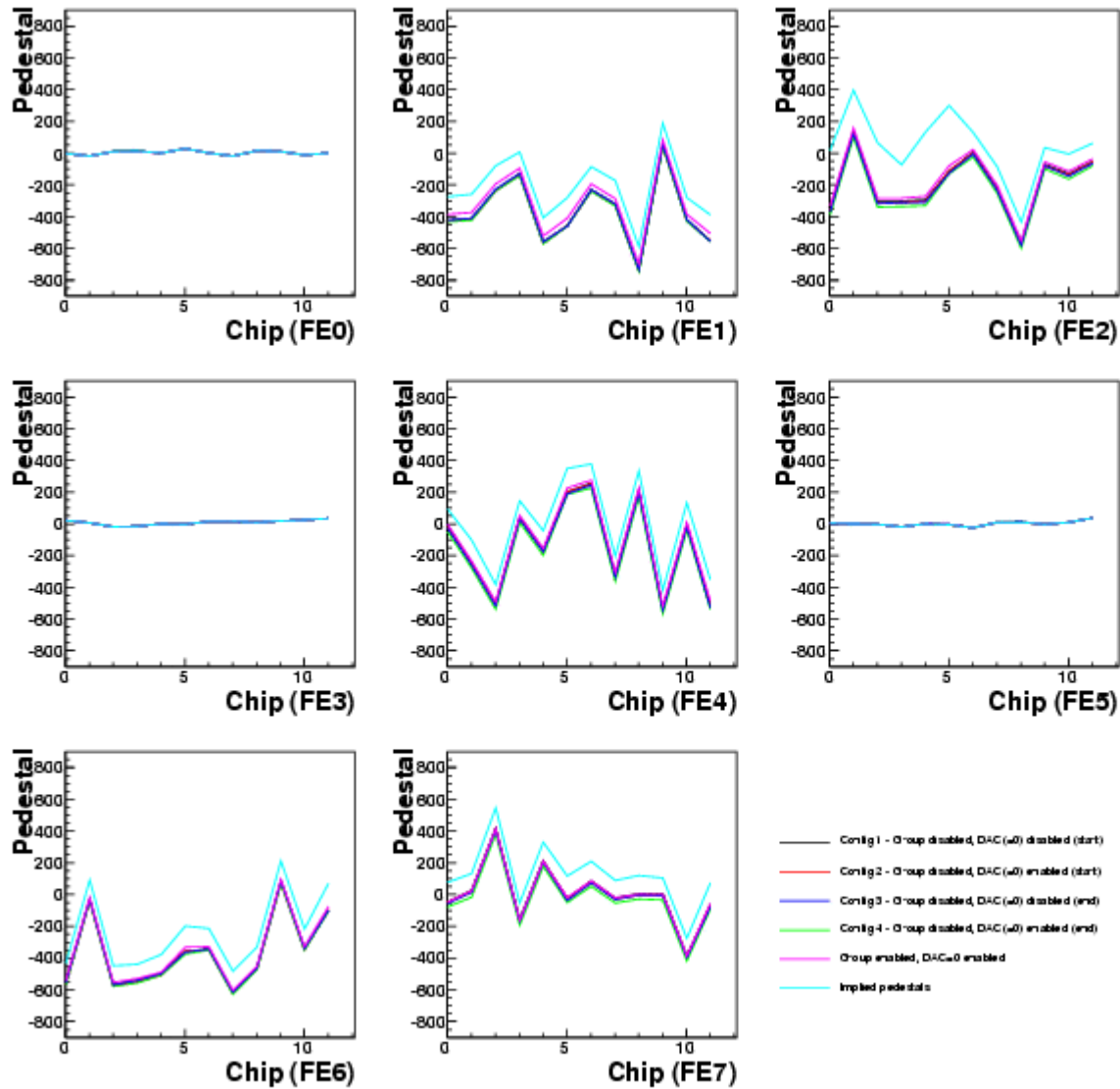
Chip-by-Chip Pedestals – Slot 7



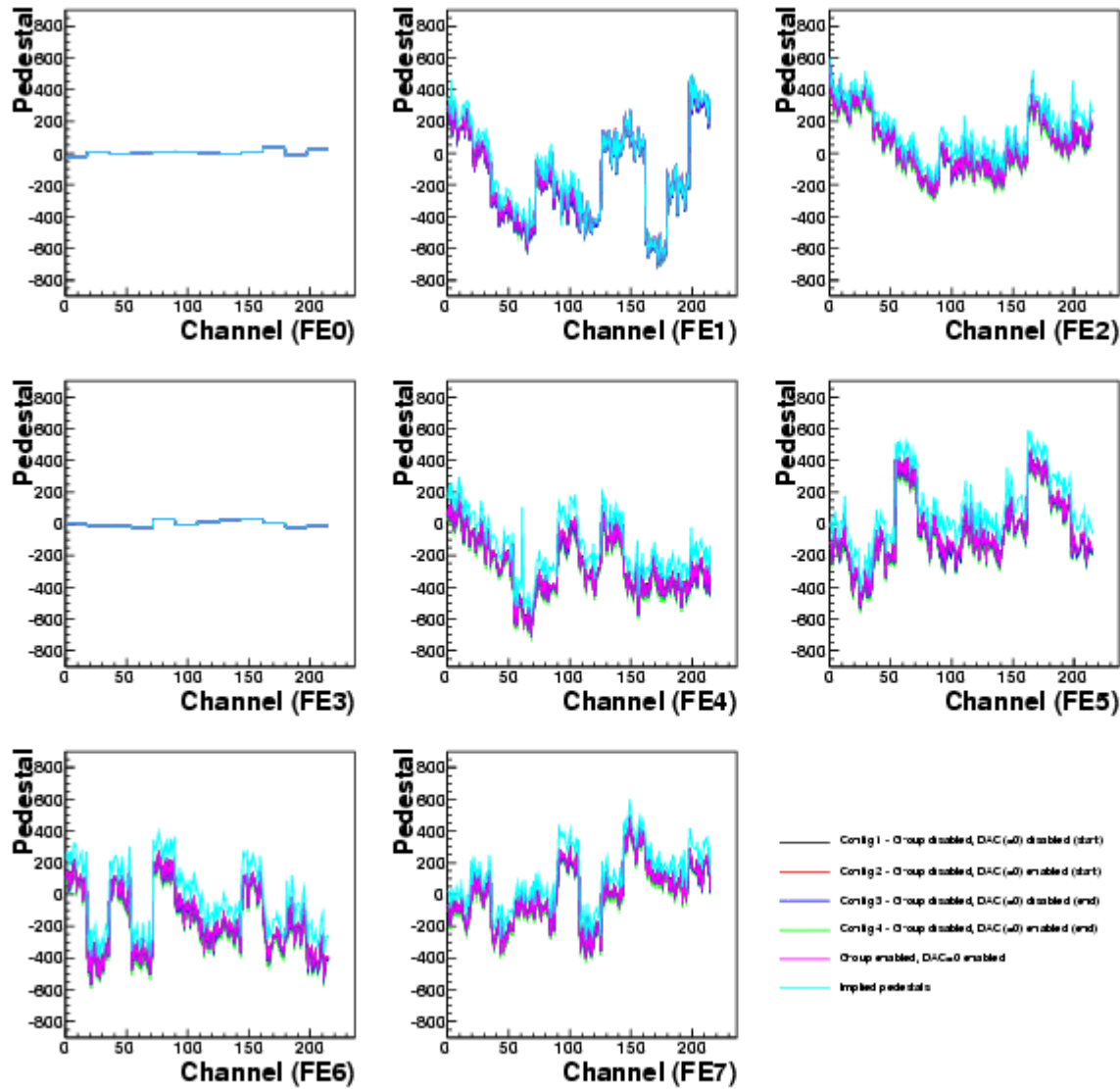
Pedestals – Slot 15



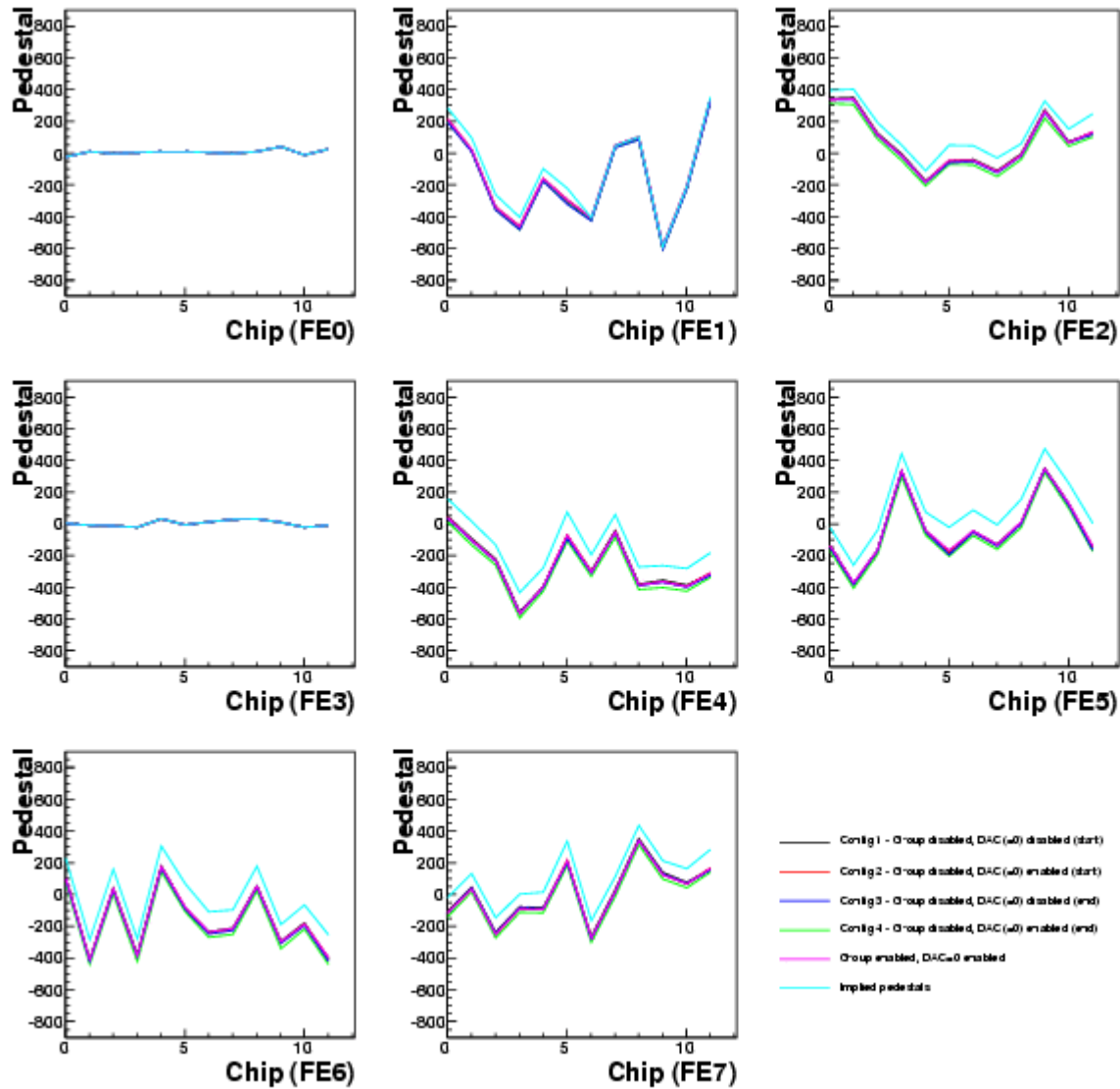
Chip-by-Chip Pedestals – Slot 15



Pedestals – Slot 19



Chip-by-Chip Pedestals – Slot 19



Summary

- Good progress made in the analysis of bad channels and pedestals.
- Need to specify the criteria which defines a channel as bad.
- Need to make the fitting more flexible so that it can deal with FEs such as FE2 of slot 7.
- Website has been set up to contain all of the bad channel and pedestal information.
- Why are the implied pedestals greater than the explicit pedestals?

Future work

- Address the issues above.
- Study the pulse shapes (HOLD).
- Study cross-talk in the system.
- Looking, ultimately, to establish a robust calibration procedure.
- ... and incorporate findings in the simulation of the test-beam data.